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DETAILED ACTION

EXAMINER'S AMENDMENT

An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

Authorization for this examiner's amendment was given in a telephone interview with Clifford Ulrich on September 17, 2004. The application has been amended as follows:

In claim 8 on line 10, delete "at least one of"; on line 11, delete "and" and insert -- or--.

In claim 39 on line 12, delete "at least one of"; on line 11, delete "and" and insert --or--.

Allowable Subject Matter

Claims 1-3, 6-8, 23, 25, 32-34, 37-40 and 42-43 are allowed over prior art.

The following is an examiner's statement of reasons for allowance:

None of the prior art teaches or suggests a focal surface for an opto-electronic imaging system having a flexible carrier substrate and at least one solid state element with a maximum thickness of approximately 20 μ m, which is flexible, thinned, and connected to the flexible carrier substrate as claimed in independent claims 1, 32 and 43.

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None of the prior art teaches or suggests a focal surface for an opto-electronic imaging system having a detector carrier configured to hold at least one detector, a flexible carrier substrate, at least one flexible thinned solid state element and a temperature control system configured to maintain the least one detector within a predetermined temperature range, wherein the detector carrier including at least one channel or being coupled to at least en peltier element as claimed in independent claims 8 and 39.

None of the prior art teaches or suggests a flexible detector for imaging recording having a flexible carrier substrate and a thinned, flexible solid state element which is connected to the flexible carrier substrate, wherein the solid state element has at least one of a thickness of approximately $10\mu m$ to $20\mu m$ and a length-to-ratio of approximately 20 to 60 as claimed in independent claims 23 and 40.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Hoon Song whose telephone number is (571) 272-2494. The examiner can normally be reached on 8:30 AM - 5 PM, Monday - Friday.



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If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Edward Glick can be reached on (571) 272 - 2490. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

HKS 9/11/104

EDWARD J. GLICK